Search Notes				
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Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/603,620	HWANG ET AL.	
Examiner	Art Unit	
Ali Bayat	2624	

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Class	Subclass	Date	Examiner
382	236,237,2 39,240,23 2,233,305	10/19/2006	A.B
375	240.19	10/19/2006	A.B
375	240.03	10/19/2006	A.B
375	240.11	10/19/2006	A.B
updated	above	10/20/2006	A.B

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
USPGPUB	TEXT	10/19/2006	A.B
USPGPUB	search	10/19/2006	A.B
1	search print ut	10/19/2006	A.B

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST(USPGPUB; USPAT; DERWENT; EPO; JPO; IBM-TEB); IEEE XPLORE; see text search history print out	10/19/2006	A.B
see interference search history print out.	10/19/2006	A.B
Consulted with Jingge Wu and Wenpeng Chen	10/19/2006	A.B